## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination GUPTA ET AL. Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Davis, Robert D; et al.; "Detecting Process Shifts with X-Bar Charts", First Quarter 1993, Production and Inventory Management Journal, 34, 1, ABI/INFORM Global, p.25-31.
	>	Deleryd, Mats; "On the Gap between theory and practice of process capability studies", 1998, The International Journal of Quality and Reliability Management, Bradford, Vol. 15, Iss. 2 pg. 178.
	V	·
	X	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.